

PATENT APPLICATION

Sheet 1 of 1

FORM PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO.	APPLICATION NO.	CONFIRMATION NO.
	200300296-1		
	APPLICANT		
	Cheolmin PARK et al.		
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REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	1A				
	1B				
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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L				
	1M				
	1N				
	1O				
	1P				

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

mw	1Q	Ernest Y. Wu et al.; "Experimental Evidence of TBD Power-Law for Voltage Dependence of Oxide Breakdown in Ultrathin Gate Oxides"; IEEE Transactions on Electron Devices, Vol. 40, No. 12, December 2002 (pp. 2244-2253).
	1R	
	1S	

EXAMINER

Magan S Walling

DATE CONSIDERED

5/9/05